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**INFORMATION DISCLOSURE CITATION**  
*(Use several sheets if necessary)*

Docket Number (Optional)

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Application Number

10/616381

Applicant(s)

Douglas Brisbin et al.

Filing Date

7/9/2003

Group Art Unit

2815  
Unknown**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
MCL	AA	5,517,046	05/14/1996	Hsing et al.	257	336	02/06/1995
MCL	AB	6,144,069	11/07/2000	Tung	257	335	08/03/1999
MCL	AC	6,177,834	01/23/2001	Blair et al.	327	566	12/02/1998
MCL	AD	6,297,533	10/02/2001	Mkhitarian	257	336	04/30/1998
MCL	AE	6,548,839	04/15/2003	Strachan et al.	257	204	02/20/2002
MCL	AF	6,566,710	05/20/2003	Strachan et al.	257	341	08/29/2001

**FOREIGN PATENT DOCUMENTS**

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

**OTHER DOCUMENTS**  
*(Including Author, Title, Date, Pertinent Pages, Etc.)*

MCL	AG	D. Brisbin et al., "Design Optimization of N-LDMOS Transistor Arrays for Hot Carrier Lifetime Enhancement," <i>International Reliability Physics Symposium Proceedings 2003</i> , pp. 608-609 (2 pages in length).
MCL	AH	D. Brisbin et al., "Hot Carrier Reliability of N-LDMOS Transistor Arrays for Power BiCMOS Applications," <i>International Reliability Physics Symposium Proceedings 2002</i> , pp. 105-110 (6 pages in length).
MCL	AI	U.S. Patent Application No. 10/266,543, filed October 8, 2002, entitled: "Method and device for improving hot carrier reliability of an LDMOS transistor using drain ring over-drive bias," by Douglas Brisbin et al., 16 pages in length.

Examiner	<i>Matthew C. Polley</i>	Date Considered
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		